

## N-Channel 650V (D-S) Power MOSFET

PRODUCT SUMMARY				
V <sub>DS</sub> (V) at T <sub>J</sub> max.	650			
R <sub>DS(on)</sub> max. at 25 °C (Ω)	V <sub>GS</sub> = 10 V	1.1		
Q <sub>g</sub> max. (nC)	25			
Q <sub>gs</sub> (nC)	2.0			
Q <sub>gd</sub> (nC)	2.7			
Configuration	Single			

Top View

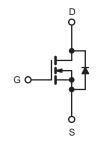
**TO-220 FULLPAK** 

#### **FEATURES**

- Low figure-of-merit (FOM) Ron x Qa
- Low input capacitance (Ciss)
- · Reduced switching and conduction losses
- Ultra low gate charge (Qq)
- Avalanche energy rated (UIS)

#### **APPLICATIONS**

- Server and telecom power supplies
- Switch mode power supplies (SMPS)
- Power factor correction power supplies (PFC)
- - High-intensity discharge (HID)
  - Fluorescent ballast lighting
- Industrial



N-Channel MOSFET

<b>ABSOLUTE MAXIMUM RATINGS</b> (T <sub>C</sub> = 25 °C, unless otherwise PARAMETER			SYMBOL			
Drain-Source Voltage			V <sub>DS</sub>	650	UNIT	
Gate-Source Voltage			V <sub>GS</sub>	± 30	V	
Continuous Dusin Comment /T. 150 °C)	\/ at 10 \/	T <sub>C</sub> = 25 °C	1	7.0	A	
Continuous Drain Current (T <sub>J</sub> = 150 °C)	V <sub>GS</sub> at 10 V	$T_C = 25 ^{\circ}C$ $T_C = 100 ^{\circ}C$	l <sub>D</sub>	5.6		
Pulsed Drain Current a			I <sub>DM</sub>	28	1	
Linear Derating Factor				1.67/1.5/0.3	W/°C	
Single Pulse Avalanche Energy b			E <sub>AS</sub>	86	mJ	
Maximum Power Dissipation			P <sub>D</sub>	83/83/31	W	
Operating Junction and Storage Temperature Range			T <sub>J</sub> , T <sub>stg</sub>	-55 to +150	°C	
Drain-Source Voltage Slope	T <sub>J</sub> = 125 °C		-1\//-1+	50	\//	
Reverse Diode dV/dt <sup>d</sup>			dV/dt	4.5	V/ns	
Soldering Recommendations (Peak Temperature) c for 10 s			300	°C		

- a. Repetitive rating; pulse width limited by maximum junction temperature. b.  $V_{DD}=50$  V, starting  $T_J=25$  °C, L=28.2 mH,  $R_g=25$   $\Omega$ ,  $I_{AS}=3.5$  A.

- c. 1.6 mm from case. d.  $I_{SD} \le I_D$ , dl/dt = 100 A/ $\mu$ s, starting  $T_J = 25$  °C.



THERMAL RESISTANCE RATINGS						
PARAMETER	SYMBOL	TYP.	MAX.	UNIT		
Maximum Junction-to-Ambient	R <sub>thJA</sub>	-	63	- °C/W		
Maximum Junction-to-Case (Drain)	R <sub>thJC</sub>	-	0.6			

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static				•	l.		
Drain-Source Breakdown Voltage	V <sub>DS</sub>	V <sub>GS</sub> =	= 0 V, I <sub>D</sub> = 250 μA	650	-	-	V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference to 25 °C, I <sub>D</sub> = 1 mA		-	0.65	-	V/°C
Gate-Source Threshold Voltage (N)	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$		2.5	-	5	V
		V <sub>GS</sub> = ± 20 V		-	-	± 100	nA
Gate-Source Leakage	$I_{GSS}$		V <sub>GS</sub> = ± 30 V		-	± 1	μA
		V <sub>DS</sub> = 650 V, V <sub>GS</sub> = 0 V		-	-	1	μΑ
Zero Gate Voltage Drain Current	$I_{DSS}$		$V_{DS} = 520 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 125 \text{ °C}$		-	10	
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 4 A	-	1.1	-	Ω
Forward Transconductance	9 <sub>fs</sub>		= 30 V, I <sub>D</sub> = 4 A	-	16	-	S
Dynamic					ı.		
Input Capacitance	C <sub>iss</sub>		V <sub>GS</sub> = 0 V,	-	860	_	
Output Capacitance	C <sub>oss</sub>	1	$V_{DS} = 100 \text{ V},$	-	120	-	
Reverse Transfer Capacitance	C <sub>rss</sub>	7	f = 1 MHz		15	-	pF
Effective Output Capacitance, Energy Related <sup>a</sup>	C <sub>o(er)</sub>	V <sub>DS</sub> = 0 V to 520 V, V <sub>GS</sub> = 0 V		-	45	-	
Effective Output Capacitance, Time Related <sup>b</sup>	C <sub>o(tr)</sub>			-	62	-	
Total Gate Charge	Qg			-	25		<b>†</b>
Gate-Source Charge	Q <sub>gs</sub>	V <sub>GS</sub> = 10 V	$V_{GS} = 10 \text{ V}$ $I_{D} = 4 \text{ A}, V_{DS} = 520 \text{ V}$		2.0	-	nC
Gate-Drain Charge	Q <sub>gd</sub>	1		-	2.7	-	1
Turn-On Delay Time	t <sub>d(on)</sub>	V <sub>DD</sub> = 520 V, I <sub>D</sub> = 4 A,		-	25	-	ns
Rise Time	t <sub>r</sub>			-	55	-	
Turn-Off Delay Time	t <sub>d(off)</sub>	00	$V_{DD} = 320 \text{ V}, I_D = 4 \text{ A},$ $V_{GS} = 10 \text{ V}, R_g = 9.1 \Omega$		70	-	
Fall Time	t <sub>f</sub>				40	-	
Gate Input Resistance	R <sub>g</sub>	f = 1 MHz, open drain		-	3.5	-	Ω
Drain-Source Body Diode Characteristic	S						
Continuous Source-Drain Diode Current	I <sub>S</sub>	MOSFET symbol showing the integral reverse p - n junction diode		-	-	7	
Pulsed Diode Forward Current	I <sub>SM</sub>			-	-	18	_ A
Diode Forward Voltage	V <sub>SD</sub>	T <sub>J</sub> = 25 °C, I <sub>S</sub> = 4 A, V <sub>GS</sub> = 0 V		-	-	1.5	V
Reverse Recovery Time	t <sub>rr</sub>	T <sub>J</sub> = 25 °C, I <sub>F</sub> = I <sub>S</sub> = 4 A, dl/dt = 100 A/µs, V <sub>R</sub> = 400 V		-	190	-	ns
Reverse Recovery Charge	Q <sub>rr</sub>			-	2.3	-	μC
Reverse Recovery Current	I <sub>RRM</sub>			<u> </u>	10	_	A

#### Notes

- a.  $C_{oss(er)}$  is a fixed capacitance that gives the same energy as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DSS}$ . b.  $C_{oss(tr)}$  is a fixed capacitance that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DSS}$ .



#### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

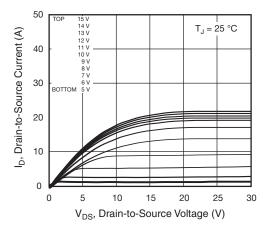


Fig. 1 - Typical Output Characteristics

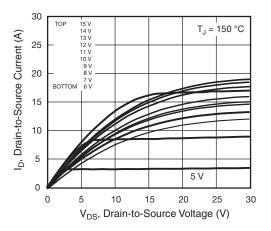


Fig. 2 - Typical Output Characteristics

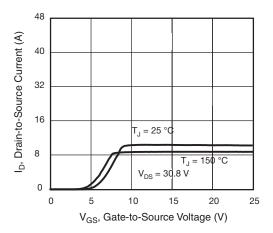


Fig. 3 - Typical Transfer Characteristics

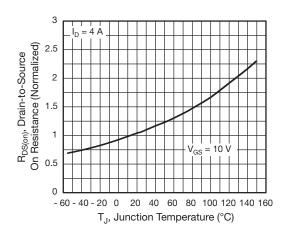


Fig. 4 - Normalized On-Resistance vs. Temperature

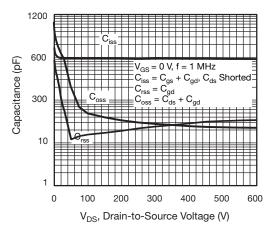


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

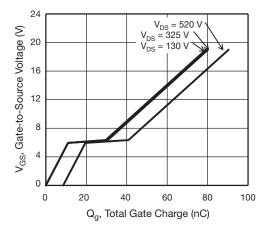


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage



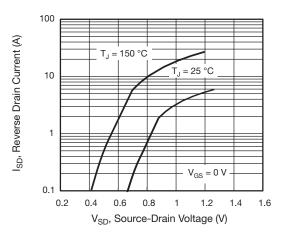


Fig. 7 - Typical Source-Drain Diode Forward Voltage

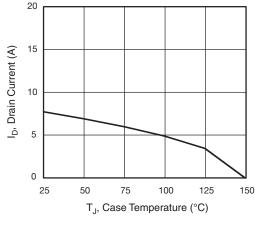


Fig. 9 - Maximum Drain Current vs. Case Temperature

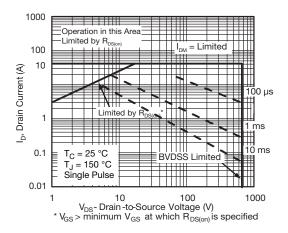


Fig. 8 - Maximum Safe Operating Area

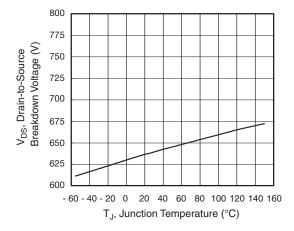


Fig. 10 - Temperature vs. Drain-to-Source Voltage

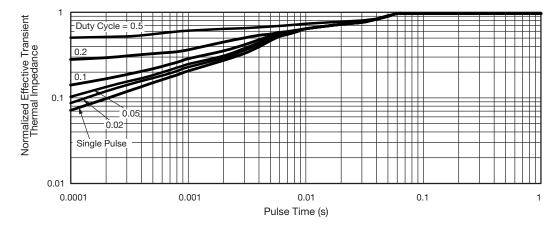


Fig. 11 - Normalized Thermal Transient Impedance, Junction-to-Case



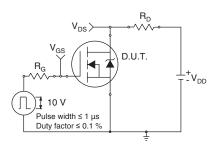


Fig. 12 - Switching Time Test Circuit

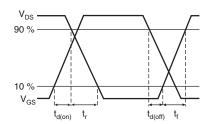


Fig. 13 - Switching Time Waveforms

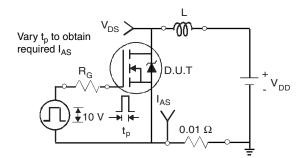


Fig. 14 - Unclamped Inductive Test Circuit

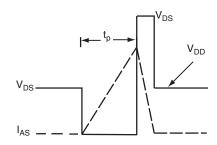


Fig. 15 - Unclamped Inductive Waveforms

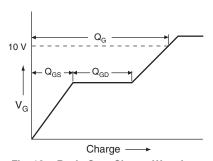


Fig. 16 - Basic Gate Charge Waveform

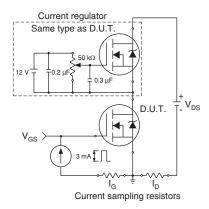
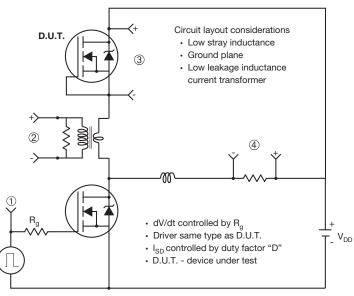


Fig. 17 - Gate Charge Test Circuit



#### Peak Diode Recovery dV/dt Test Circuit



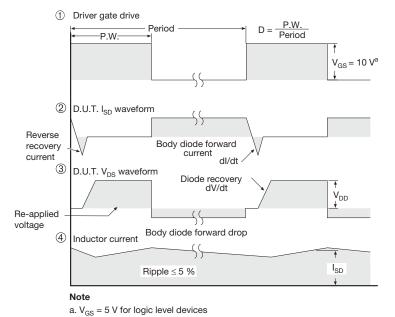
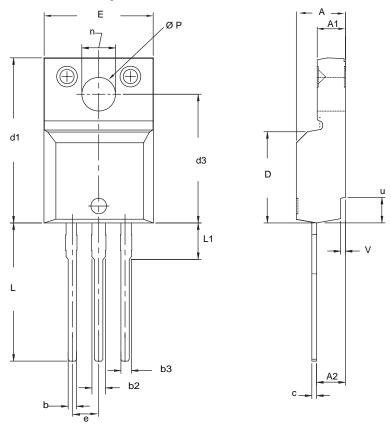


Fig. 18 - For N-Channel



### **TO-220 FULLPAK (HIGH VOLTAGE)**



	MILLIMETERS			HES	
DIM.	MIN.	MAX.	MIN.	MAX.	
А	4.570	4.830	0.180	0.190	
A1	2.570	2.830	0.101	0.111	
A2	2.510	2.850	0.099	0.112	
b	0.622	0.890	0.024	0.035	
b2	1.229	1.400	0.048	0.055	
b3	1.229	1.400	0.048	0.055	
С	0.440	0.629	0.017	0.025	
D	8.650	9.800	0.341	0.386	
d1	15.88	16.120	0.622	0.635	
d3	12.300	12.920	0.484	0.509	
E	10.360	10.630	0.408	0.419	
е	2.54 BSC		0.100 BSC		
L	13.200	13.730	0.520	0.541	
L1	3.100	3.500	0.122	0.138	
n	6.050	6.150	0.238	0.242	
ØР	3.050	3.450	0.120	0.136	
u	2.400	2.500	0.094	0.098	
V	0.400	0.500	0.016	0.020	
ECN: X09-0126-Rev. B, 2 DWG: 5972	6-Oct-09				

#### Notes

- To be used only for process drawing.
   These dimensions apply to all TO-220, FULLPAK leadframe versions 3 leads.
   All critical dimensions should C meet C<sub>pk</sub> > 1.33.
   All dimensions include burrs and plating thickness.

- 5. No chipping or package damage.



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